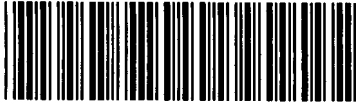


Search Notes

Application/Control No.

10/755,144

Examiner

Michael Y. Won

Applicant(s)/Patent under
Reexamination

HATIME, HICHAM

Art Unit

2155

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|------------------|----------|----------|
| 709 | 224, 233, 235 | 8/8/2007 | MW |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------|----------|----------|
| 709 | 233 | 8/9/2007 | MW |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
|---|----------|------|
| EAST: USPAT; USPG-PUB; DERWENT; EPO; JPO | 8/8/2007 | MW |
| NPL SEARCH: IEEE | 8/9/2007 | MW |
| DISCUSSED CASE WITH PRIMARY: PHILIP TRAN | 8/9/2007 | MW |
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